



UNITED STATES PATENT AND TRADEMARK OFFICE

COMMISSIONER FOR PATENTS
 UNITED STATES PATENT AND TRADEMARK OFFICE
 WASHINGTON, D.C. 20231
 www.uspto.gov



Bib Data Sheet

CONFIRMATION NO. 9892

SERIAL NUMBER 10/026,560	FILING DATE 12/27/2001 RULE	CLASS 365 714	GROUP ART UNIT 2018 2133	ATTORNEY DOCKET NO. 108075-00072
APPLICANTS Masayuki Takeshige, Kasugai, JAPAN; Sumitaka Hibino, Kasugai, JAPAN; Kenji Yamada, Kasugai, JAPAN; <i>CB</i>				
** CONTINUING DATA *****				
** FOREIGN APPLICATIONS ***** JAPAN 2001-174101 06/08/2001 <i>CB</i>				
IF REQUIRED, FOREIGN FILING LICENSE GRANTED ** 01/28/2002				
Foreign Priority claimed <input checked="" type="checkbox"/> yes <input type="checkbox"/> no	35 USC 119 (a-d) conditions met <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after Allowance	STATE OR COUNTRY JAPAN	SHEETS DRAWING 10	TOTAL CLAIMS 18
Verified and Acknowledged <i>Chen</i>	Examiner's Signature <i>Chen</i>	Initials		INDEPENDENT CLAIMS 3
ADDRESS AREN'T FOX KINTNER PLOTKIN & KAHN, PLLC Suite 600 1050 Connecticut Avenue, N.W. Washington, DC 20036-5339				
TITLE Test method and test system for semiconductor device				
FILING FEE RECEIVED 740	FEES: Authority has been given in Paper No. _____ to charge/credit DEPOSIT ACCOUNT No. _____ for following:	<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees (Filing) <input type="checkbox"/> 1.17 Fees (Processing Ext. of time) <input type="checkbox"/> 1.18 Fees (Issue) <input type="checkbox"/> Other _____ <input type="checkbox"/> Credit		